

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 854063.666	APPLICATION NO. 10/081,134
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANTS Ernesto Lasalandra et al.	
		FILING DATE February 20, 2002	GROUP ART UNIT 2858

JUL 3 1 2003  
PATENT & TRADEMARK OFFICE

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
ah	AA 4,054,833	10/18/77	Briefer	324	60 C	
am	AB 4,860,232	08/22/89	Lee et al.	364	571.04	
an	AC 2003/0052699	03/20/03	Lasalandra et al.	324	662	
ad						
ae						
af						
ag						
ah						
aj						
aj						

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES <input checked="" type="checkbox"/> NO <input type="checkbox"/>
ay	AK 2 706 038	12/09/94	FR (+ Abstract in English)	<input type="checkbox"/> X
al				
am				
an				
ao				

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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AQ		
AR		

EXAMINER	DATE CONSIDERED
ay he	2/3/04

\* EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).

FORM PTO-1449 (REV.7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 854063.666	APPLICATION NO. 10/081,134		
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	AK						
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att	AP	Lemkin, M. et al., "A Three-Axis Micromachined Accelerometer with a CMOS Position-Sense Interface and Digital Offset-Trim Electronics," <i>IEEE Journal of Solid-State Circuits</i> , 34(4):456-468, April 1999.					
	AQ						
	AR						
EXAMINER				DATE CONSIDERED			
<i>Amy He</i>				<i>6/11/03</i>			
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Date: 06/17/02

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